FCC ID: 2AYJK-SPUCKA

Portable device
According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.
According to KDB447498 D01 General RF Exposure Guidance V06
The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:
[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]·[√f(GHZ)] ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	4.61	2.89	5±1	6	3.98	<5	1.23400	3.00	YES
	2.441	4.82	3.03	5±1	6	3.98	<5	1.24398	3.00	YES
	2.480	4.8	3.02	5±1	6	3.98	<5	1.25388	3.00	YES
π/4-DQPSK	2.402	5.28	3.37	5±1	6	3.98	<5	1.23400	3.00	YES
	2.441	5.32	3.40	5±1	6	3.98	<5	1.24398	3.00	YES
	2.480	5.5	3.55	5±1	6	3.98	<5	1.25388	3.00	YES
8-DPSK	2.402	5.52	3.56	5±1	6	3.98	<5	1.23400	3.00	YES
	2.441	5.7	3.72	5±1	6	3.98	<5	1.24398	3.00	YES
	2.480	5.82	3.82	5±1	6	3.98	<5	1.25388	3.00	YES
BLE 1M	2.402	4.46	2.79	4±1	5	3.16	<5	0.98020	3.00	YES
	2.440	4.67	2.93	4±1	5	3.16	<5	0.98793	3.00	YES
	2.480	4.71	2.96	4±1	5	3.16	<5	0.99599	3.00	YES
BLE 2M	2.402	4.57	2.86	4±1	5	3.16	<5	0.98020	3.00	YES
	2.440	4.78	3.01	4±1	5	3.16	<5	0.98793	3.00	YES
	2.480	4.88	3.08	4±1	5	3.16	<5	0.99599	3.00	YES

Conclusion:
For the max result : 1.25388 ≤ 3.0 for 1g SAR, SAR is not required.

Signature: **Date:** 2025-07-10

Alex Li

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